

ABSTRACT OF THE DISCLOSURE

A part of a scan path lying in the  $x$  th stage of a test circuit is formed by successively connecting the FF11 $x$  standing at the head of the  $x$ th stage to the FF1 $m$  $x$  standing at the end of the same in series. The scan path connects the scan input SIN with the input terminal of the FF11 $n$  standing at the head of the  $n$  th stage, and successively connects the FFs arranged in the second to  $(n-1)$  th stages in series, after restarting from the output terminal of the FF1 $m$  $n$  standing at the end of the  $n$ th stage. The output terminal of the FF1 $m$  $(n-1)$  standing at the end of the  $(n-1)$  th stage is connected with the input terminal of the FF111 standing at the head of the first stage, and, finally, the output terminal of the FF1 $m$ 1 standing at the end of the first stage is connected with the scan output SOT.